

Jedat signs Distribution Agreement with Pollen Metrology

Jedat Inc. (Head office: Chuo-ku, Tokyo, President and CEO: Kazutoshi Matsuo, hereinafter "Jedat") has signed a distributorship agreement with POLLEN METROLOGY (hereinafter "POLLEN"), which provides a comprehensive AI-driven process control platform (hereinafter "Smart3") that shortens the time to market for semiconductor manufacturing. Through this partnership, Jedat will be able to provide POLLEN's Smart3 to customers in the semiconductor manufacturing field in Japan, automating the analysis of complex data related to development and manufacturing processes, thereby shortening the time to market for new semiconductor processes.

POLLEN was founded in France in 2014 and has been developing Smart3 for over 10 years, focusing on image-based data analysis for metrology and inspection, and is expanding its business to blue-chip customers in the United States, Asia, and Europe, accelerating the identification of the root cause of yield loss through fine image analysis.

POLLEN's speciality is its image analysis technology, which allows high-precision segmentation of objects from image data such as SEM (scanning electron microscope), TEM (transmission electron microscope), optical microscope, STEM (scanning transmission electron microscope), and acoustic microscope, measurement, analysis tools, and supervised and unsupervised defect detection tools to speed up process design, optimize production yield, and improve the ROI of process, measurement, and inspection hardware.

POLLEN's field is one in which semiconductor companies with their own fabs have a relatively high share of in-house tools, but it is becoming difficult to continue maintenance due to labor-saving measures. POLLEN also offers a software development kit that can handle the infrastructure part.

In the future, Jedat and POLLEN will work closely together, closely monitor trends in the Japanese market, and work together to further expand their solutions.

Kazutoshi Matsuo, President and CEO of Jedat, commented:

"We are pleased to be able to offer POLLEN innovative, high quality products to create high added value to semiconductor manufacturing field in Japan. Through this partnership, we hope to provide our customers with a wide range of choices and efficient solutions. "

Johann Foucher, President & CEO of POLLEN, commented:

"We look forward to working with Jedat to expand POLLEN products in the Japanese semiconductor manufacturing field and enable more productive processes for our customers. I am confident that the project will be successful."

【Company Profile】

Jedat Inc. <https://www.jedat.co.jp/>

- Established: 2004
- Business details: Development, sales, and support of design automation software for semiconductor and display design, and semiconductor design.
- Location: HSB Teppouzu, 1-1-12 Minato, Chuo-ku, Tokyo 104-0043
- Representative: Kazutoshi Matsuo, President and CEO

POLLEN METROLOGY <https://www.pollen-metrology.com/>

- Established: 2014
- Business details: Provides a comprehensive AI-driven process control platform that shortens time to market for semiconductor manufacturing. Providing image analysis tools with a focus on image-based data analysis for measurement and inspection, the company is based in France and operates with blue-chip customers in the US, Asia and Europe.
- Address: 122 rue du Rocher de Lorzier, 38430 Moirans, France
- Representative: Johann Foucher, President and CEO

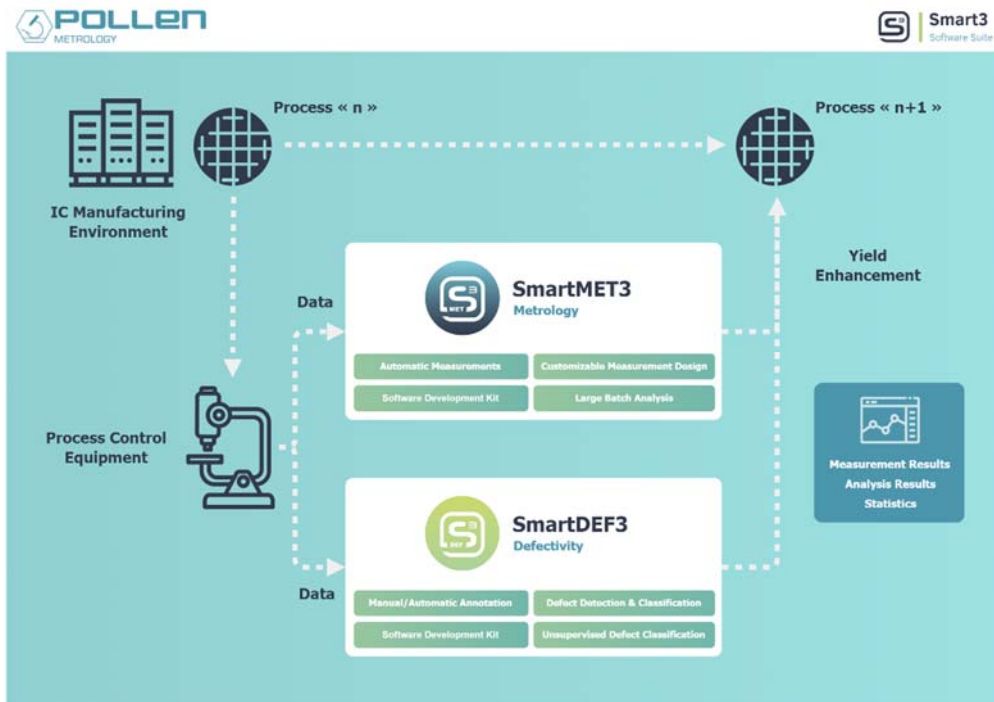
[Contact information regarding this matter]

Jedat Inc.

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Appendix : Product Structure



■ SmartMET3

Accelerate the development of your manufacturing processes by automating the processing of images from any type of microscopes.

SmartMET3 makes it possible to create in a few clicks image processing supervised models from artificial intelligence in order to extract all the critical dimensions of the manufactured materials. The SmartMET3 software platform is compatible with images from various microscopes: SEM, TEM, STEM, Optical, Acoustic, AFM (...).

SmartMET3 is delivered with its API (Application Programming Interface) and its SDK (Software Development Kit) in order to allow its implementation in a production cycle and the complete automation of previously created metrology models or internal homemade customers algorithms.

■ SmartDEF3

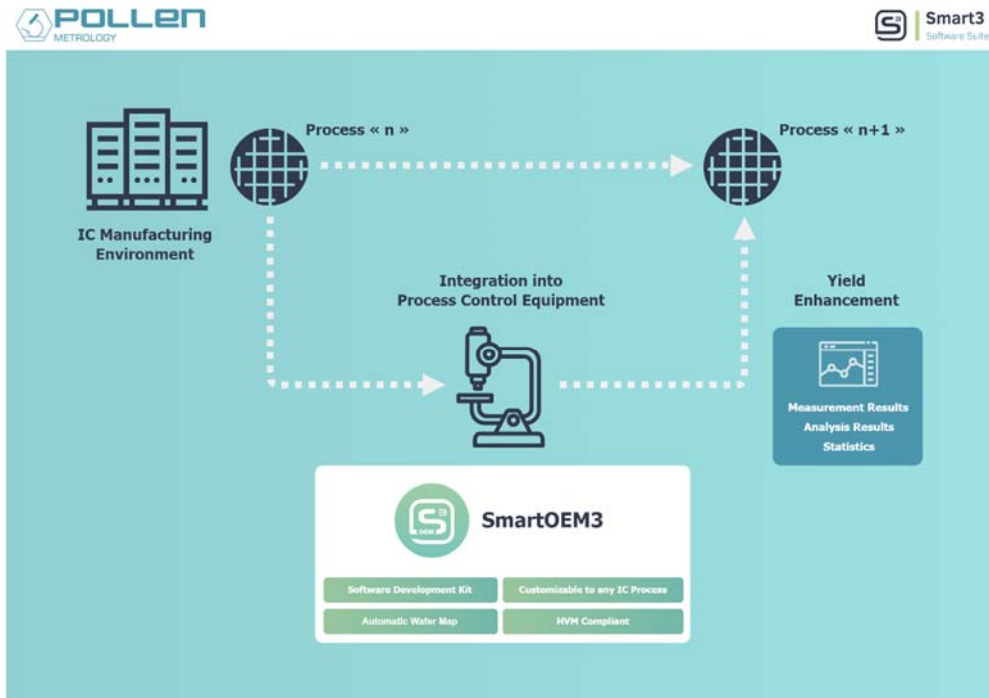
Enhance the yields of your manufacturing processes by automating the analysis of your defectivity data.

SmartDEF3 allows you to create supervised or unsupervised artificial intelligence models in a few clicks in order to detect, classify and measure defects in your manufactured materials. The SmartDEF3 software platform is compatible with images from various microscopes such as: SEM, TEM, STEM, Optics, Acoustics, AFM (...). The analysis can be done at the pattern

level or the wafer level.

SmartDEF3 is delivered with its API (Application Programming Interface) and its SDK (Software Development Kit) in order to allow its implementation in a production cycle and the complete automation of previously created defectivity models or internal homemade customers algorithms.

■SmartOEM3



■SmartOEM3

Integrate Smart3 technology either SmartMET3 and/or SmartDEF3 into any type of microscope to increase the ROI (Return on Investment) of the metrology/Inspection hardware and extend the process capabilities with higher accuracy, flexibility and scalability.

SmartOEM3 makes it possible to create in less than 3 months a AI-driven process control software that can be embedded into any type of microscope hardware (SEM, TEM, STEM, Optical, Acoustic, AFM (...)). Hardware suppliers can save several years of internal development to create their own internal software based on Smart3 software framework while leveraging their internal algorithm library.

SmartOEM3 is delivered with its API (Application Programming Interface) and its SDK (Software Development Kit) in order to allow its implementation in a production cycle and the complete automation of previously created metrology models or internal homemade customers algorithms.